



**SWTEST**

PROBE TODAY, FOR TOMORROW

2025 CONFERENCE

# Broadband Attenuators using Thin Film for Wafer Sort



**Pratik Ghate, Ph.D.**

# Agenda

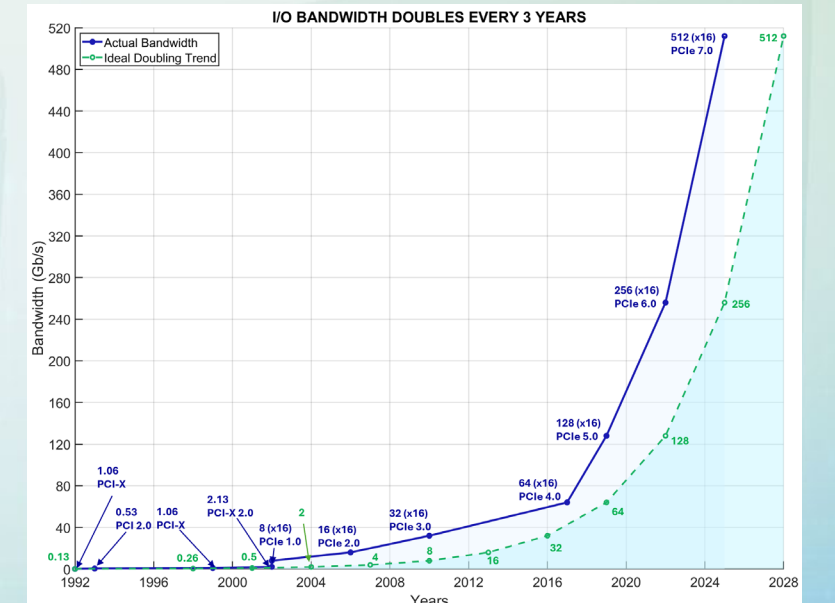
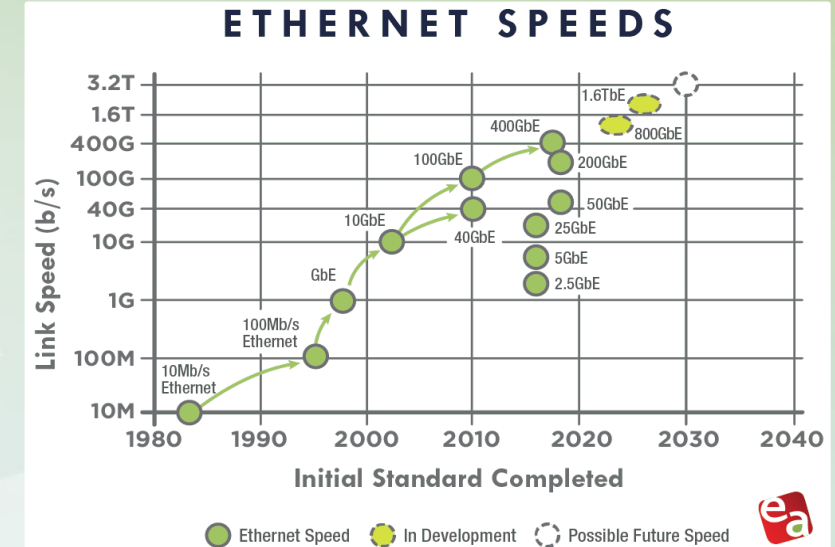
- **Market Drivers**
- **Attenuators**
- **Design and Test Setup**
- **Results**
- **Future Work**

The background of the slide features a light blue and green gradient. On the left side, there are three stylized palm trees in shades of green and blue. In the center-right, there is a faint, light blue illustration of a modern building with large windows and a curved facade.

# Market Drivers

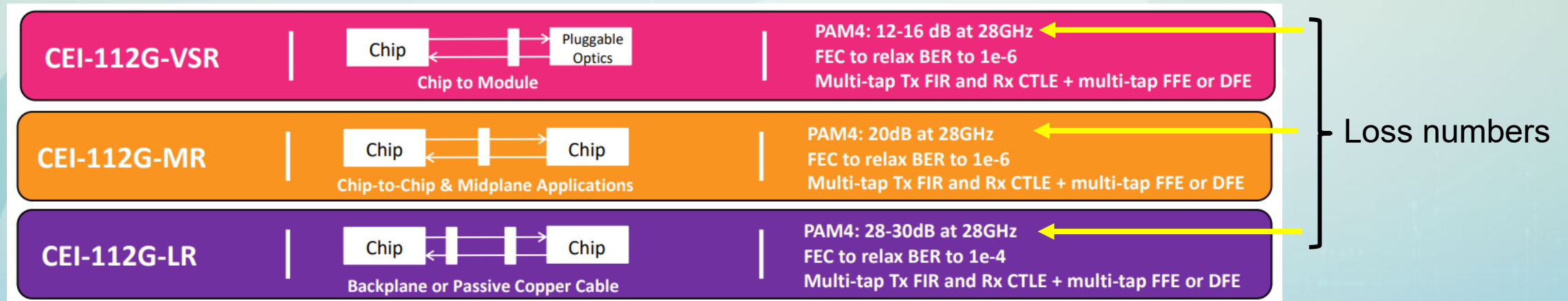
# AI Applications Driving High Data Rates

- The rise of cloud computing and AI has significantly increased the demand for high-speed SerDes (Serializer/Deserializer) chips utilizing PAM4 (Pulse Amplitude Modulation 4-level) signaling
- Real-time AI applications like autonomous driving, real time analytics, robotics etc. require sub-millisecond latency
- Data centers rely on high-speed digital communication systems, doubling bandwidth every 3 years to keep up with AI needs
- To meet these needs, development efforts are focused on moving to 448Gbps, where 224Gbps is now being deployed



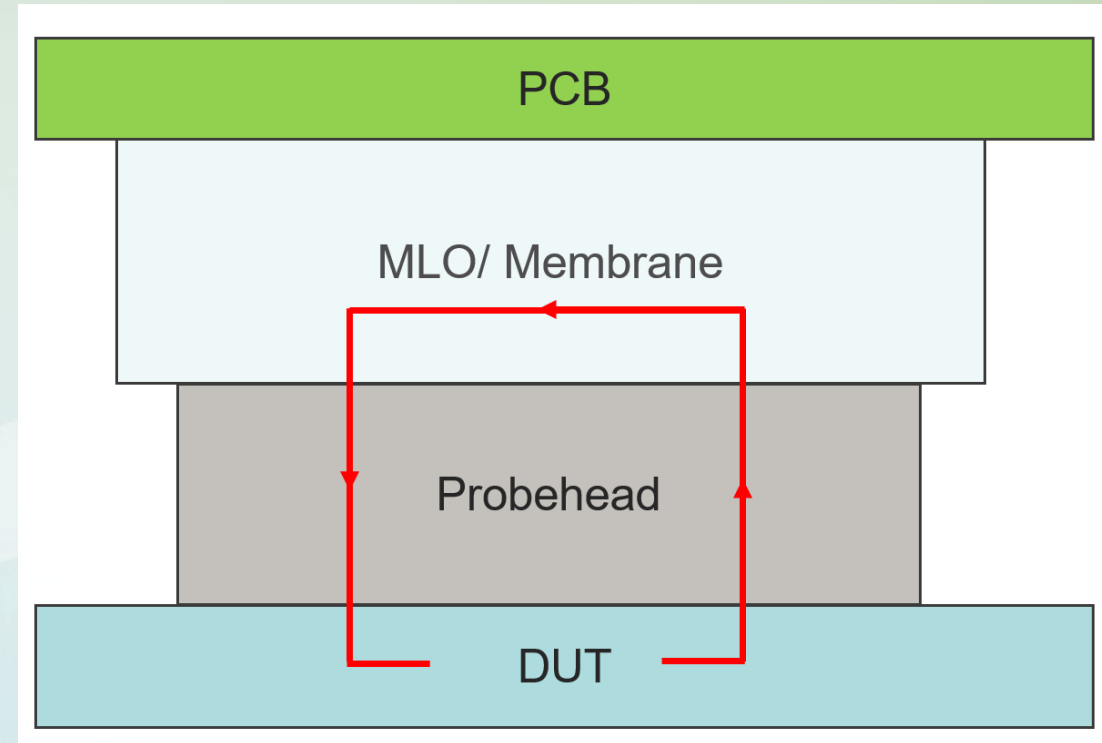
# End Module Impacts Loss

- To enable next generation data rates, it is necessary to address the interoperability requirements as defined in the communication standards
- In particular, we need to emulate the loss numbers at wafer sort to get highest possible performance to ensure correctly identifying good and bad die
- Different applications have different module types leading to different loss numbers and require different equalization techniques



# Adding Loss at Wafer Sort

- Receivers for high-speed digital applications like SERDES and PCIe Gen 7 receive highly attenuated signals due to long transmission paths
- In wafer sort loopback testing, signal paths are short and have minimum attenuation (signal loss), as compared to a real communication channel
- Adding attenuators in the probe card is essential to prevent signal clipping and non-linear distortion





# Matching Module Loss

- How can loss be added at wafer sort?

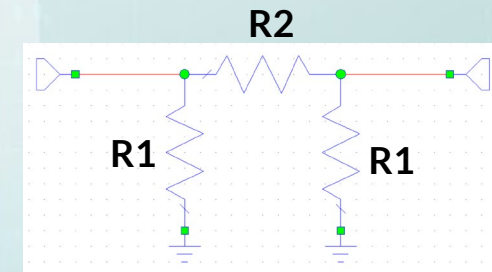
- Connectorized attenuators ✗
  - Only matched to 50 ohms
  - Too large to fit more than a few on the PCB
  - Requires complex routing to get signals out of the PCB/MLO
- SMT Attenuators ✗
  - Only matched to 50 ohms
  - Single-Ended format only
  - Long lead times
- Custom Attenuation Network ✓
  - Can match any impedance
  - Can be design for single and differential mode
  - Short lead times for off-the-shelf components



Connectorized Attenuator



SMT Attenuator



Pi-  
Attenuator

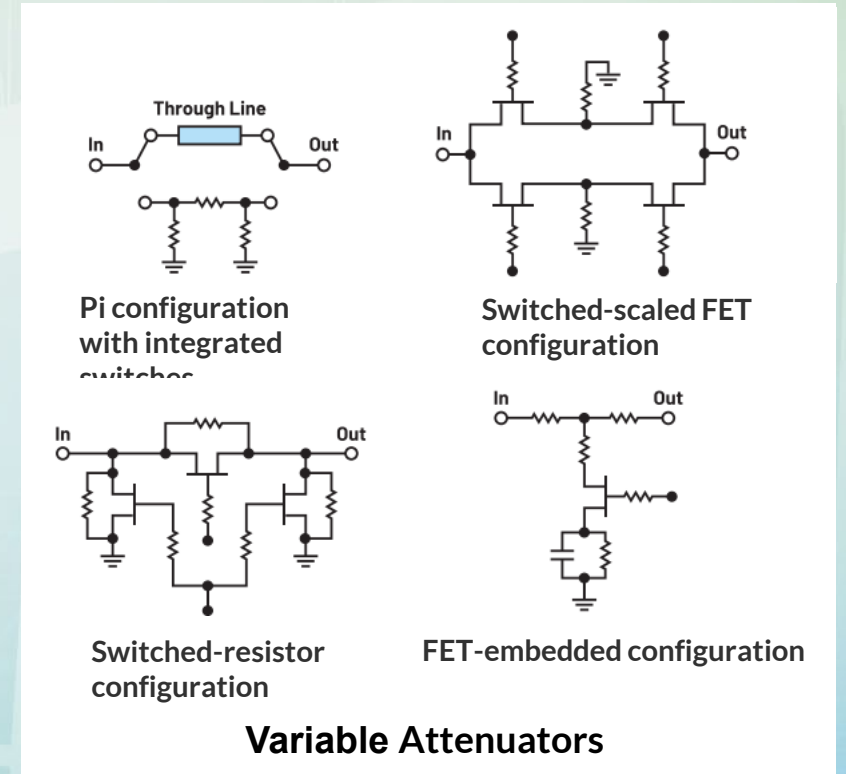
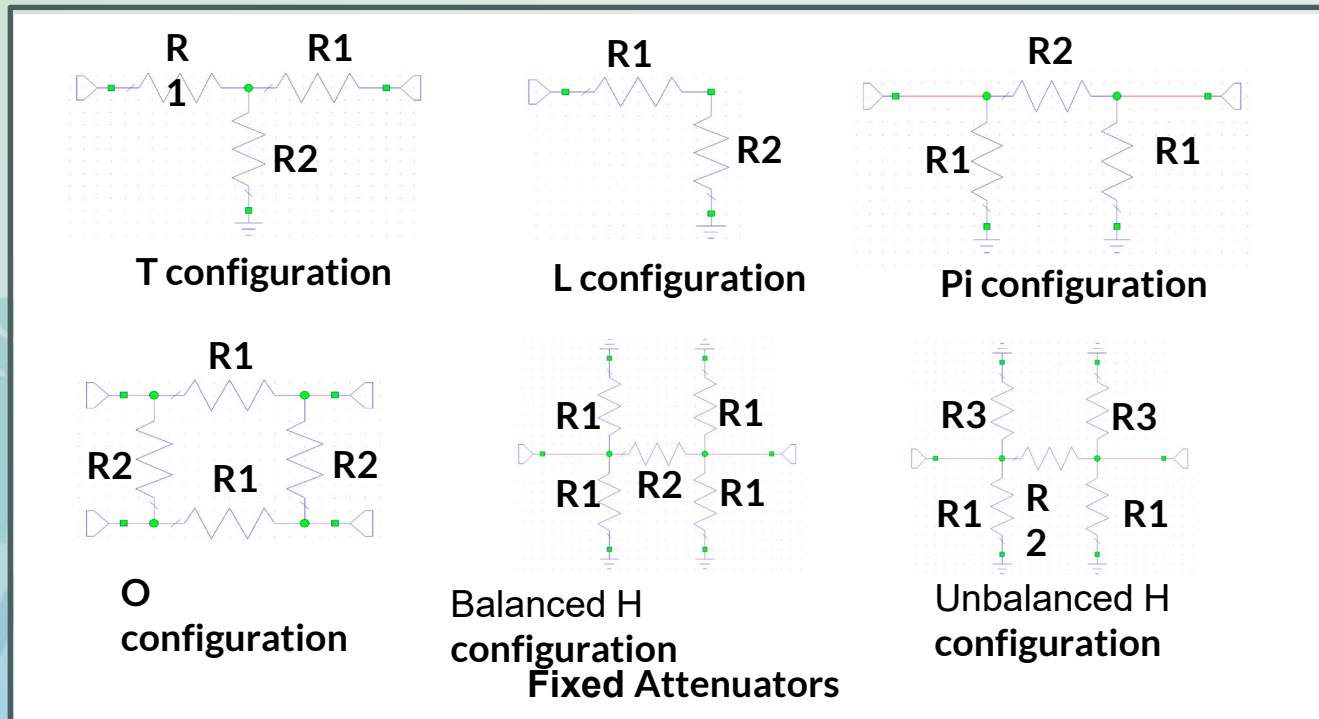
# Attenuators



# Attenuators

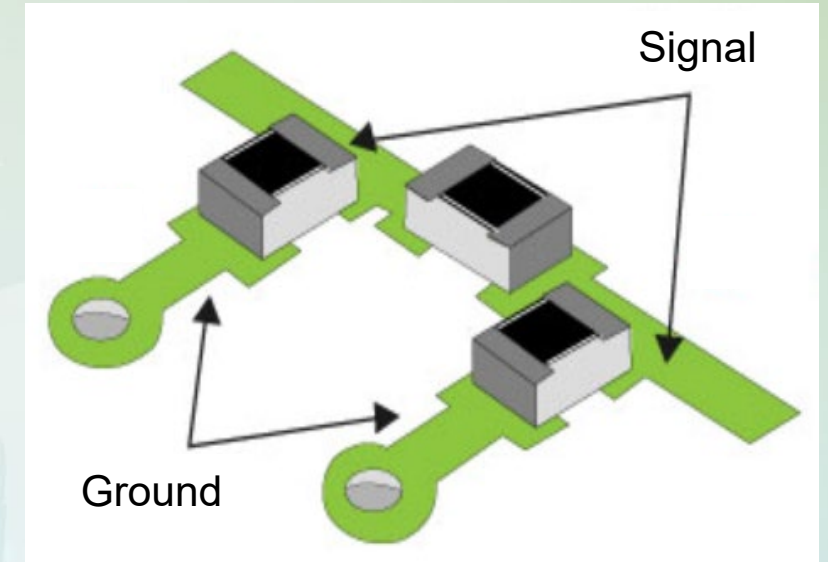
- What are Attenuators?

- Passive components that reduce signal power without distorting waveform
- Available in fixed or variable types
- Characterized by attenuation value (e.g., 10 dB, 12 dB, 15 dB)



# Disadvantages of Existing Methodology

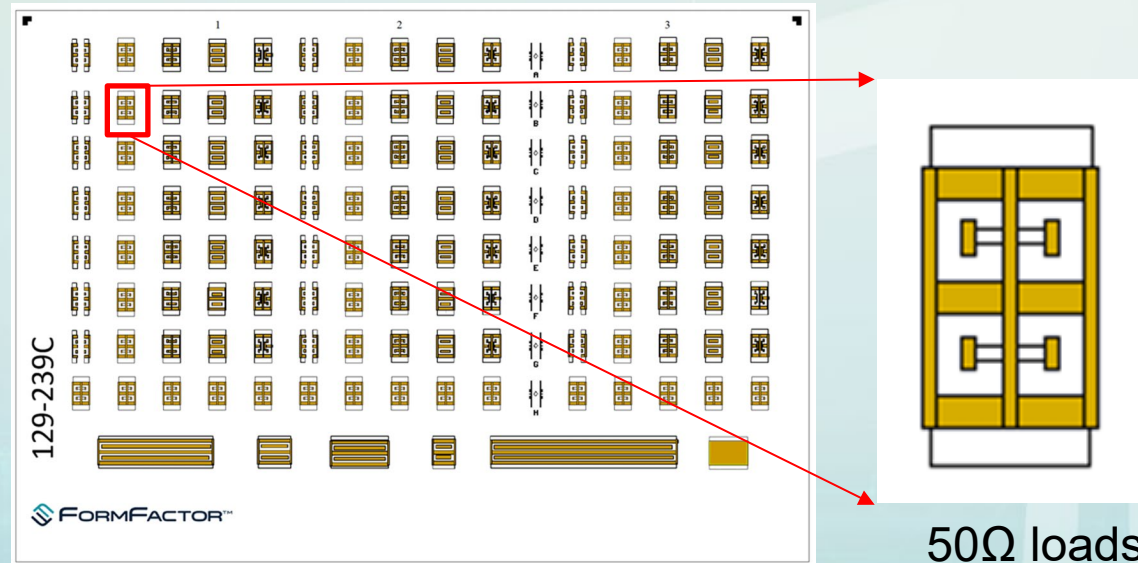
- Limited to narrowband
  - Not a compact footprint
  - Poor control on EM parasitics
- Harder to replace individual components
- Attenuation depends on available value of surface mount resistors
- Active circuits require tuning to achieve broadband attenuation resulting
  - Complex circuitry
  - Manufacturing challenges
  - Yield loss
  - High cost



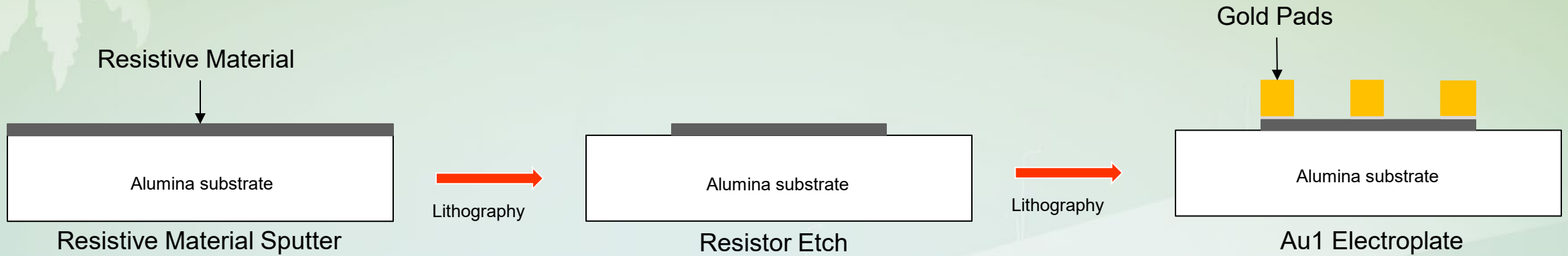
SMT components

# Why Thin Films?

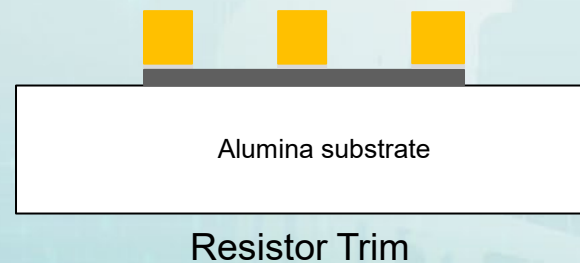
- FFI make resistors on calibrations substrates, with bandwidths capable  $>110\text{GHz}$
- Process is tightly controlled to achieve desired resistance values
- We decided to use the same process to make attenuators
- We can design for non  $50\Omega$  load values, for single and differential configuration



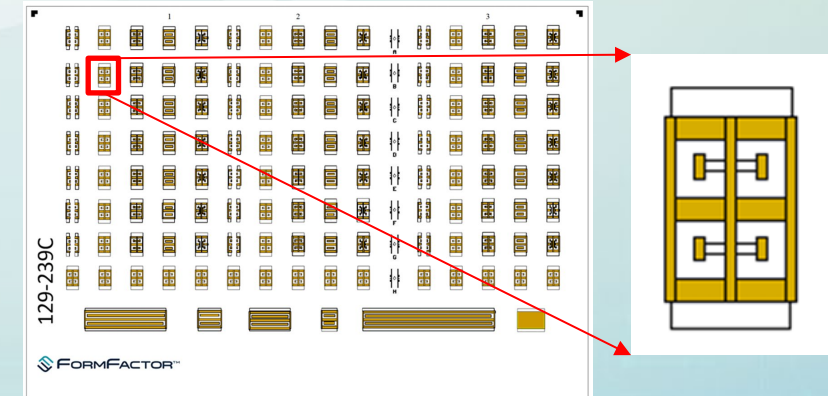
# Thin Film Resistors



$$R_{\text{Load}} = R_s * (\text{Length}/\text{Width})$$



Lithography



Final Product



# Design and Test Setup



# Calibration Strategy



VNA



Coaxial Cable



Coax Calibration



E-Probe



2<sup>nd</sup> Tier on Cal Sub

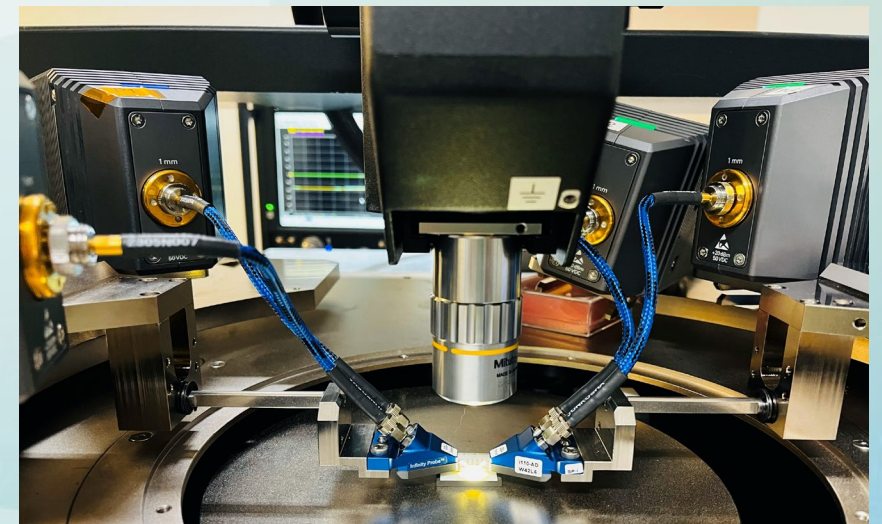
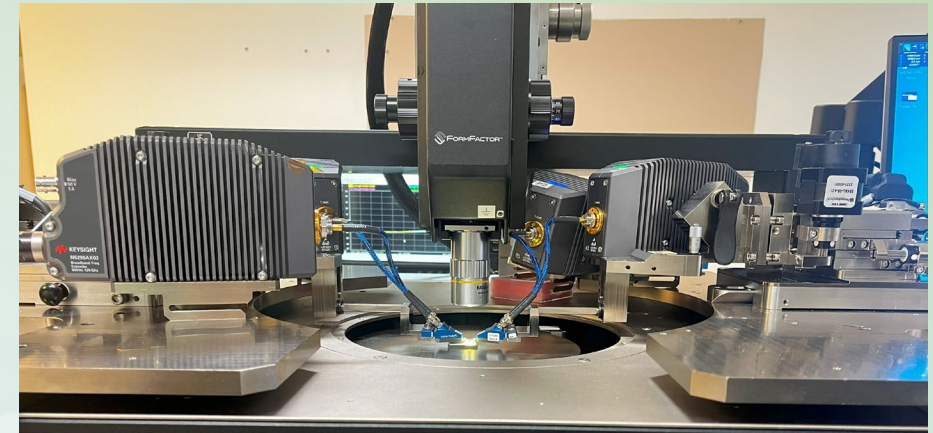


Wafer/ DUT Measurements

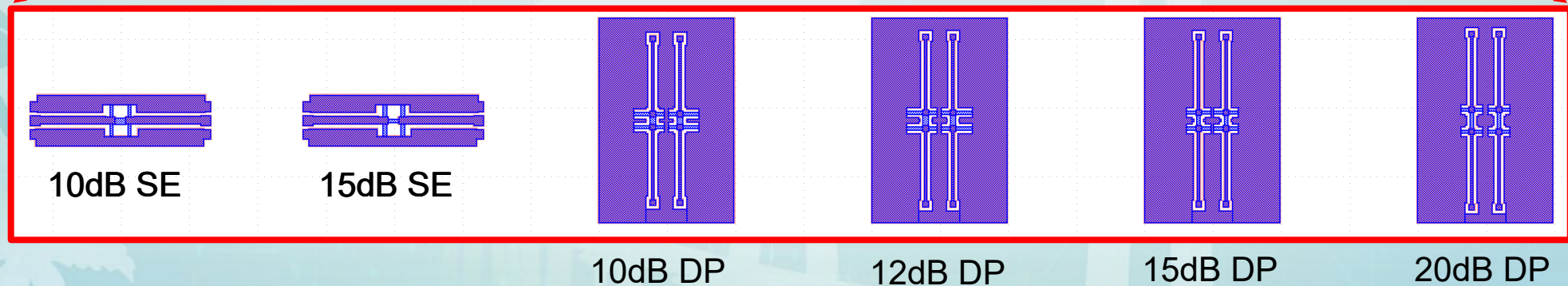
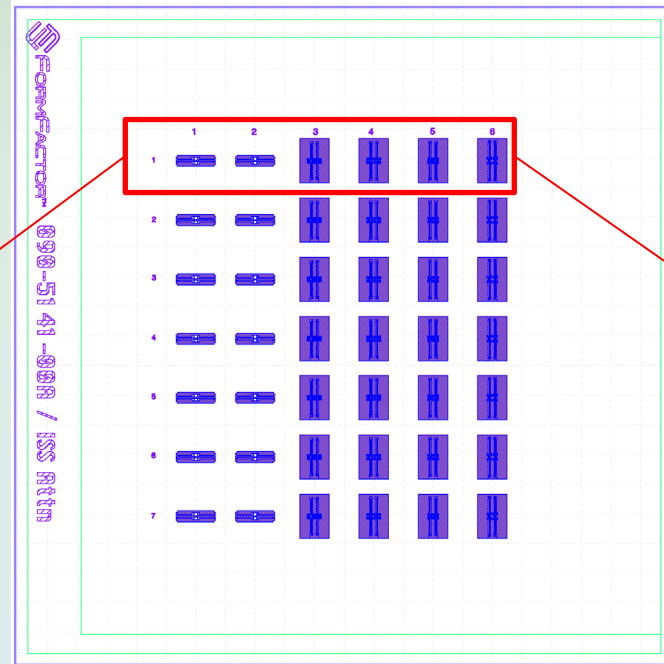


# Experimental Setup

- FFI Summit 12000 semi-auto station
  - I110-D-GSGSG-100
  - I110-GSG-100
- Keysight PNA with mmWave test set and 4-port capability
  - 50 MHz – 110 GHz
  - 50 MHz steps (11000 Points)
- Keysight Mechanical Calibration Module
- Calibration Substrate - 2<sup>nd</sup> Tier
  - 129-239C – Differential (GSGSG) - 100um- 125um
  - 138-357 – Single (GSG) - 100um- 125um

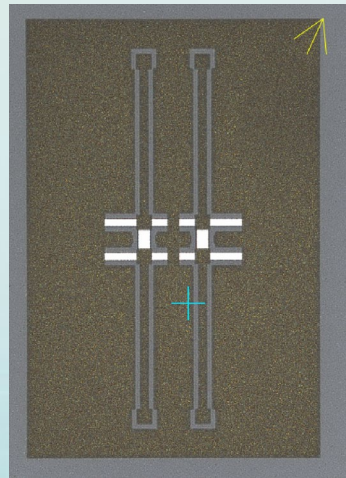


# H-Attenuator Design

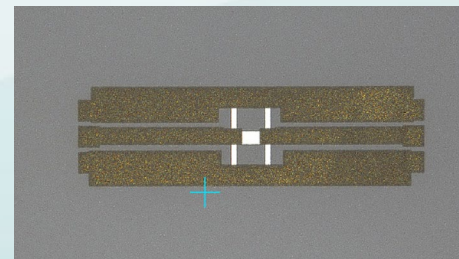


# Why H Attenuators?

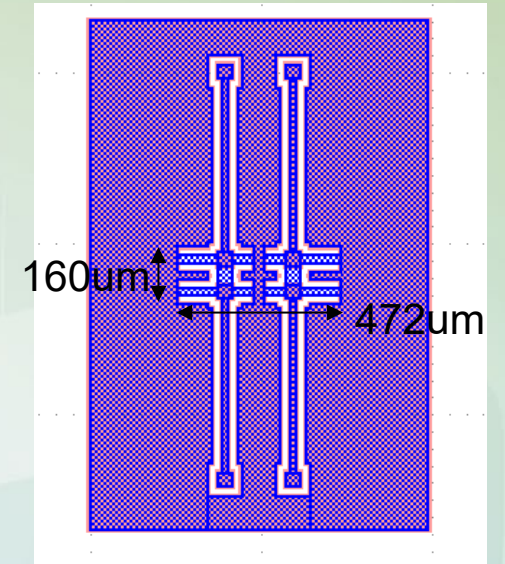
- Stable broadband performance
- Suitable for single and differential configurations
- Better EM parasitics
- Tolerant to process variations
- Better thermal distribution



10dB DP



10dB SE



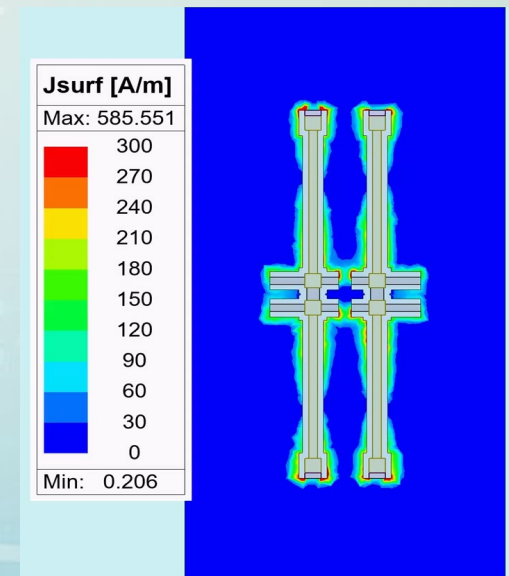
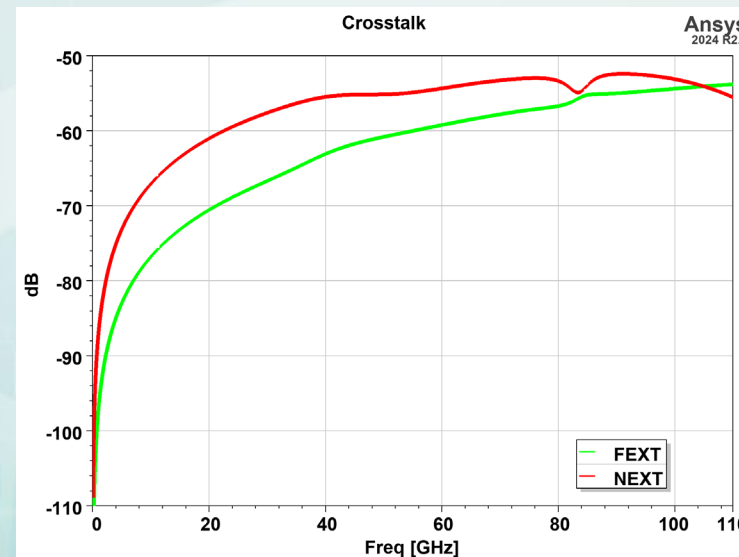
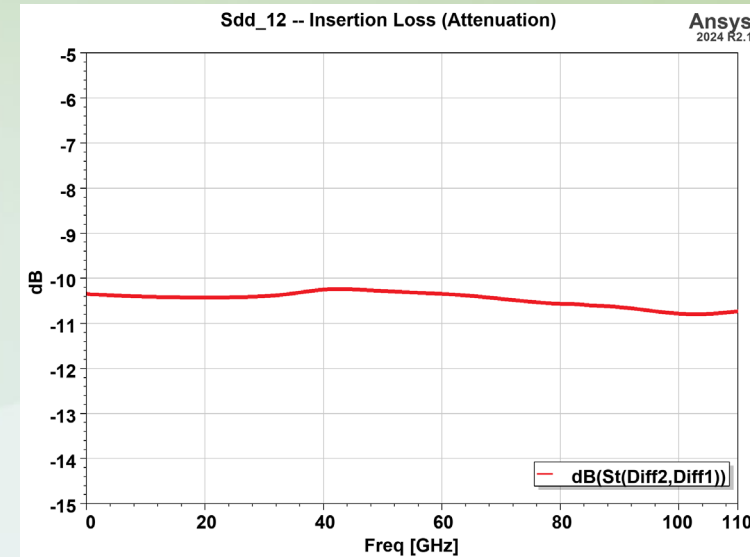
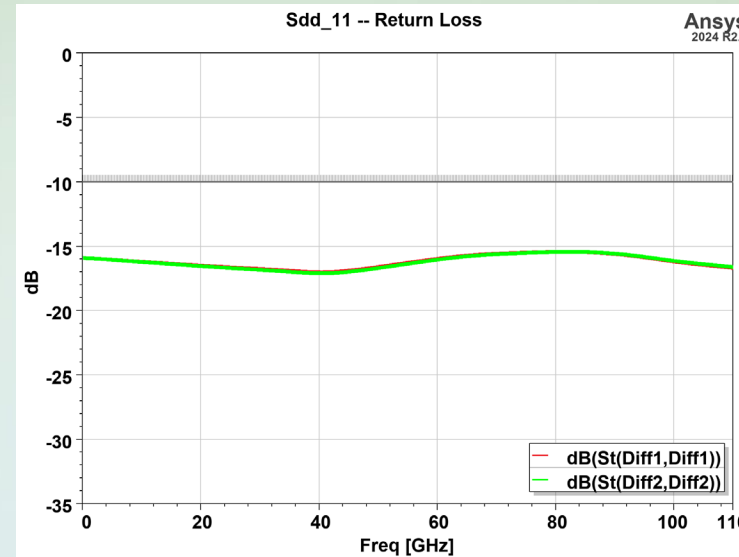
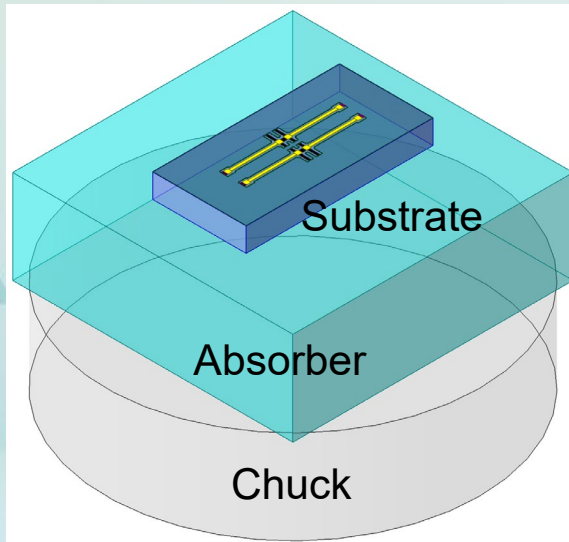
10dB DP



# Results

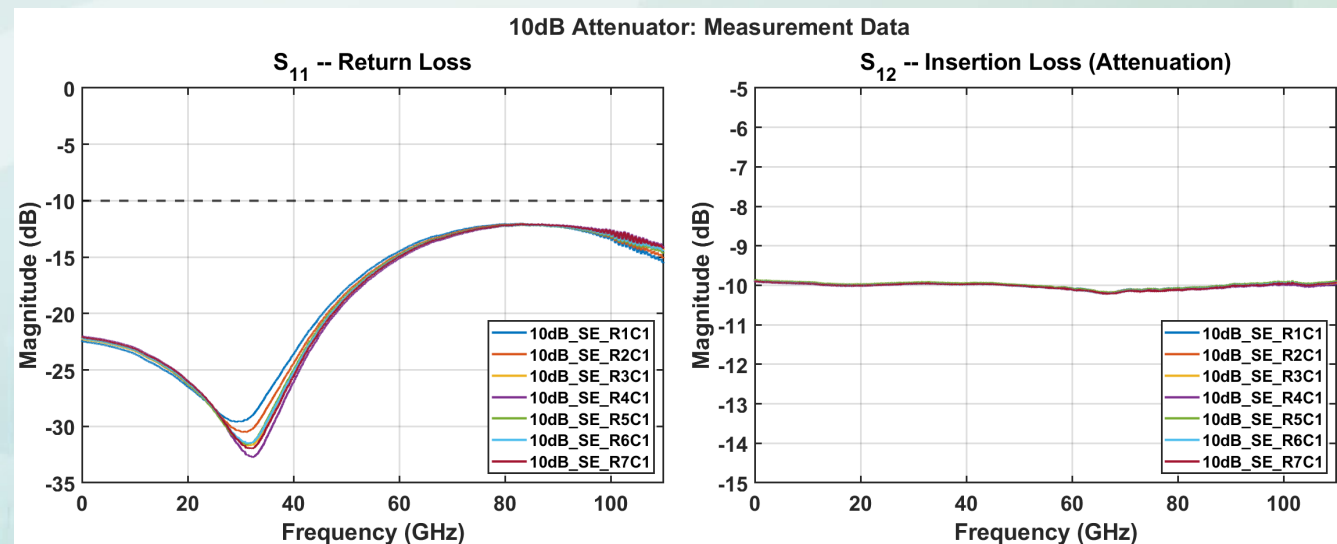
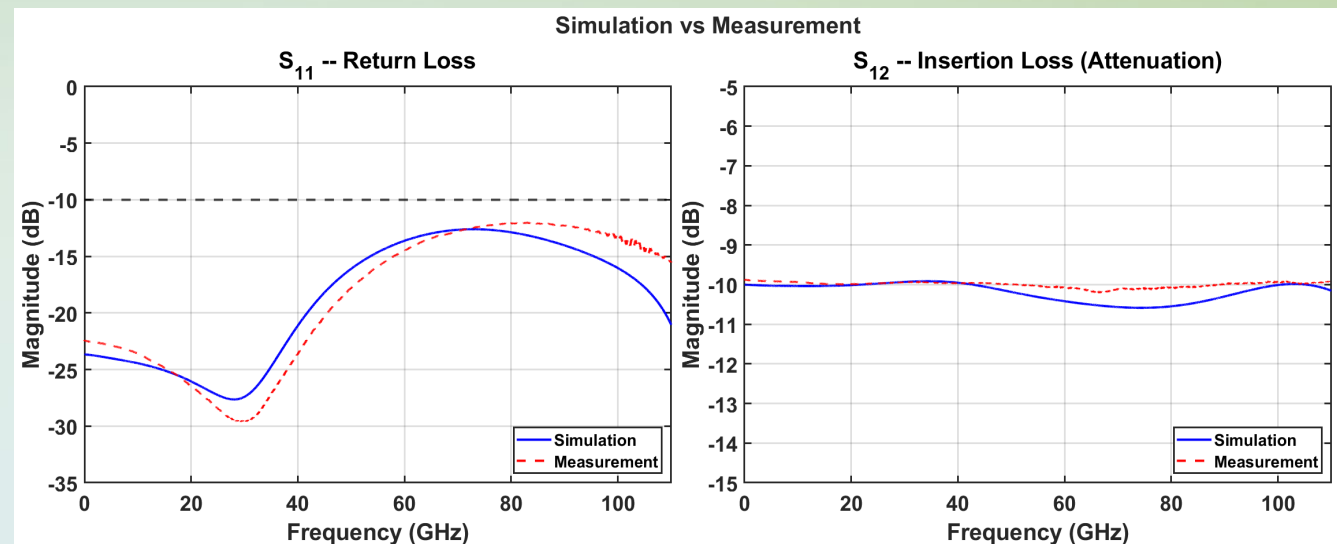
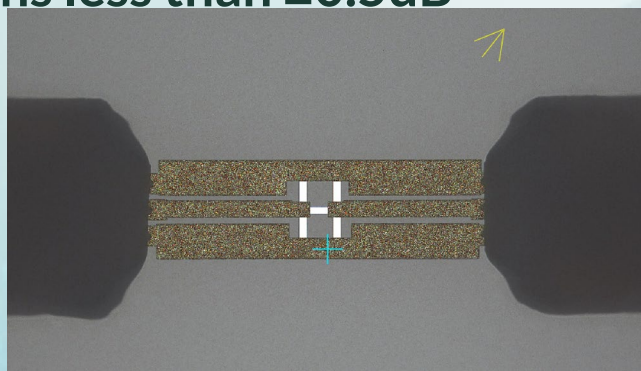
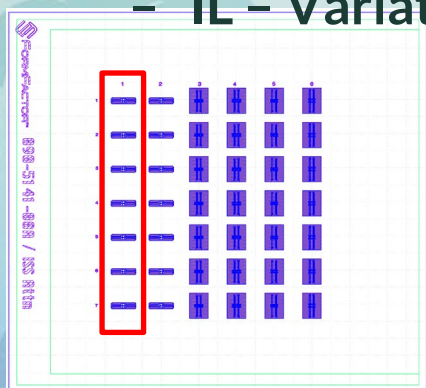
# Simulation Results

- Ansys HFSS 2024 R1
- Over Simulated performance
  - RL < -15dB till 110GHz
  - IL - Variations less than  $\pm 0.5$ dB
  - Crosstalk - Better than 50dB



# 10dB Single Ended

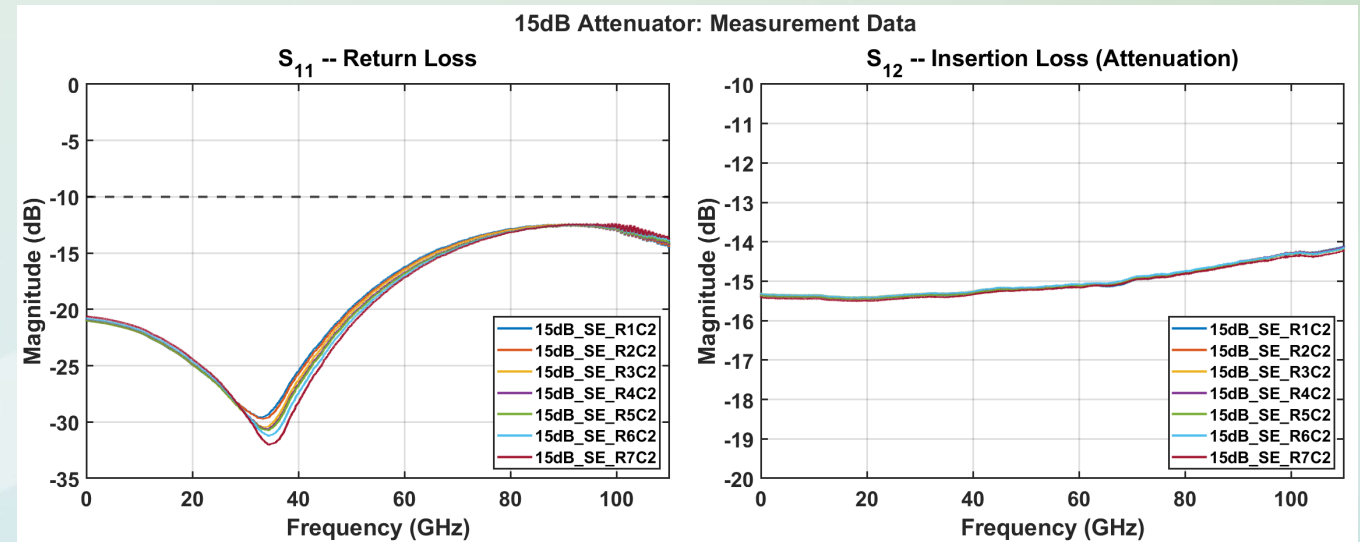
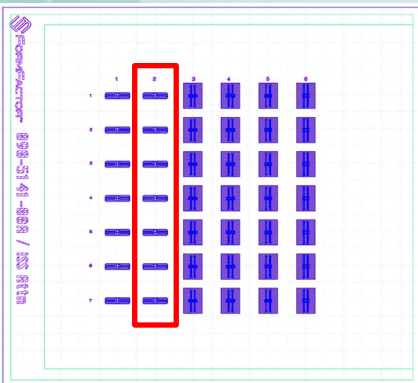
- Measured data matches very closely with 3D EM simulations.
- Some RL difference >70GHz between measurement and simulations, but follow similar trend
- Over measured performance
  - RL < -12dB till 110GHz
  - IL - Variations less than  $\pm 0.5$ dB





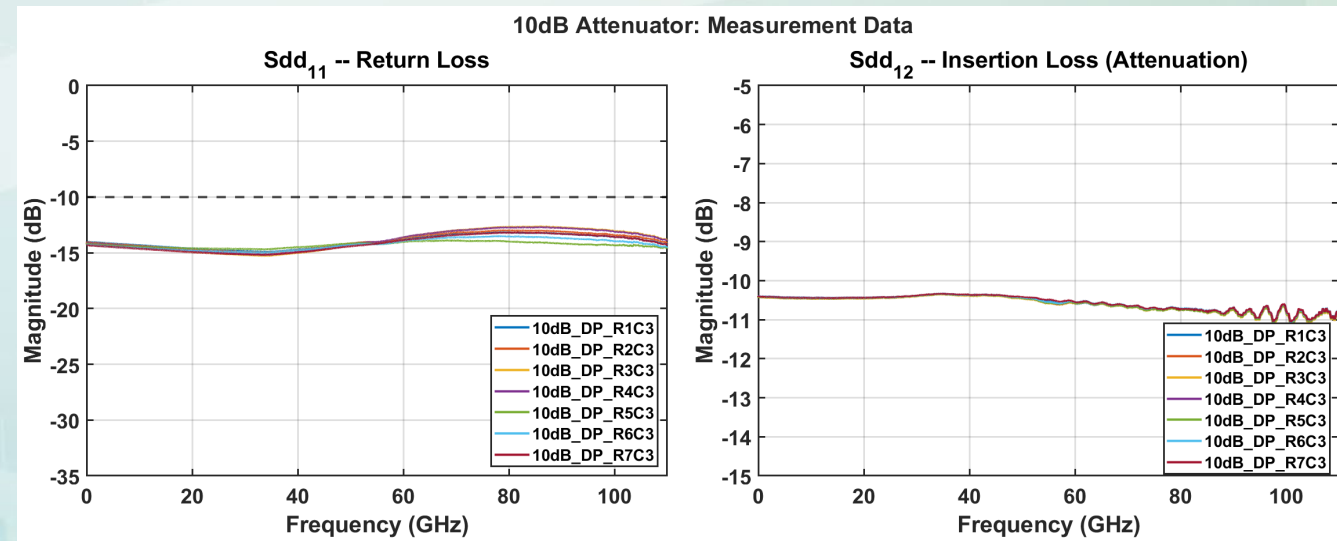
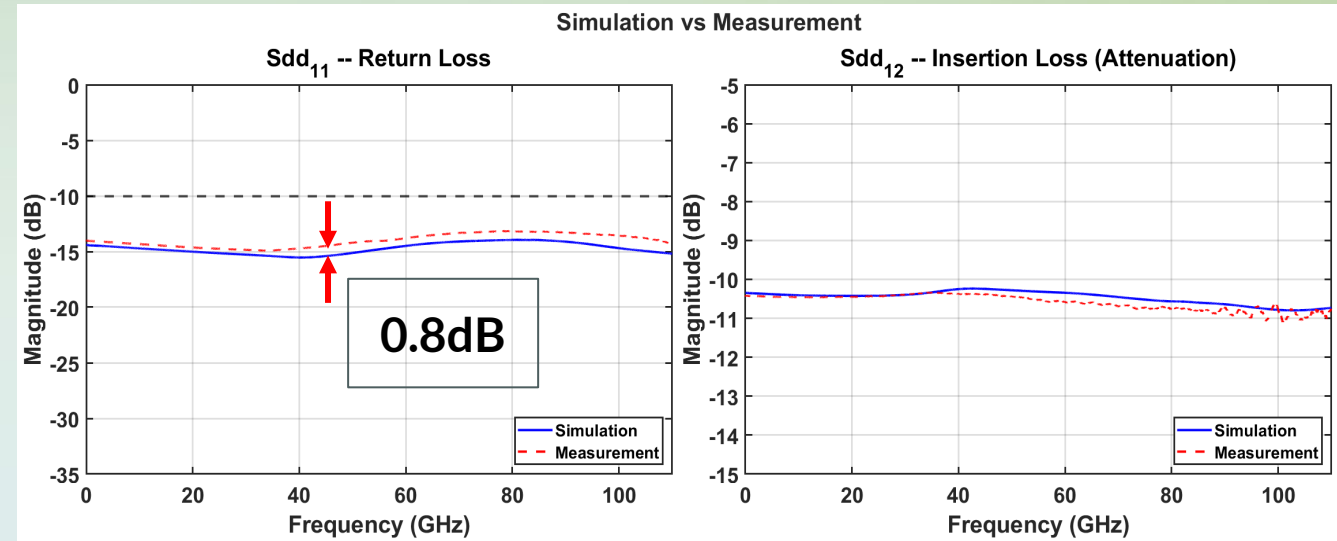
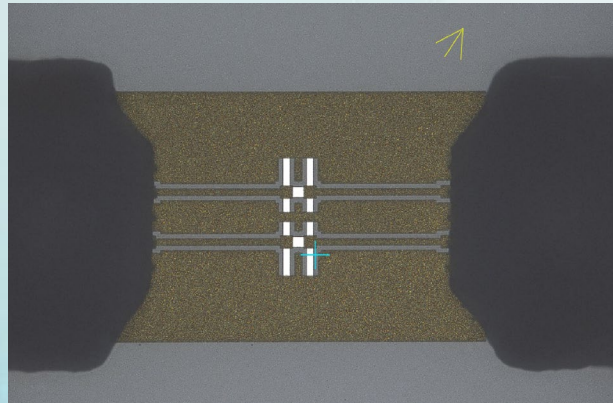
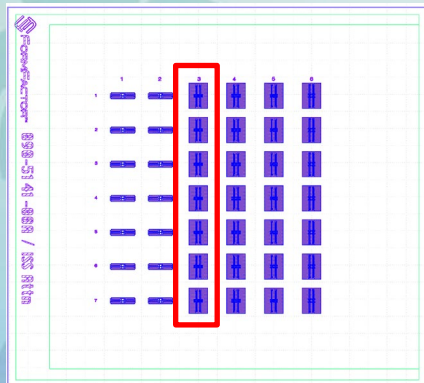
# 15dB Single Ended

- Measured attenuation values matches very closely with 3D EM simulations.
- Over measured performance
  - RL < -12dB till 110GHz
  - IL - Variations less than  $\pm 0.5$ dB



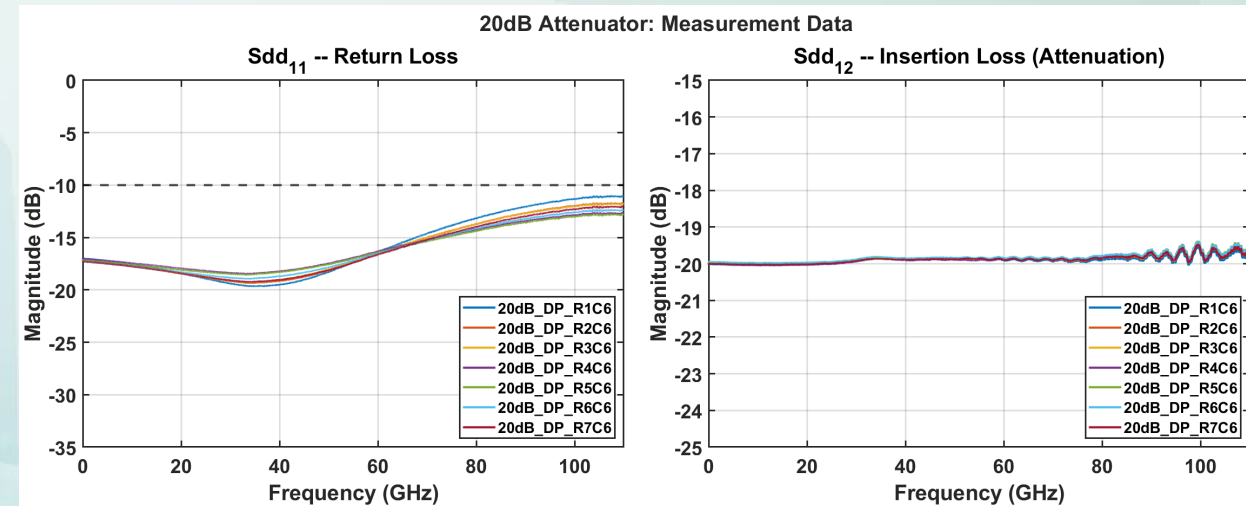
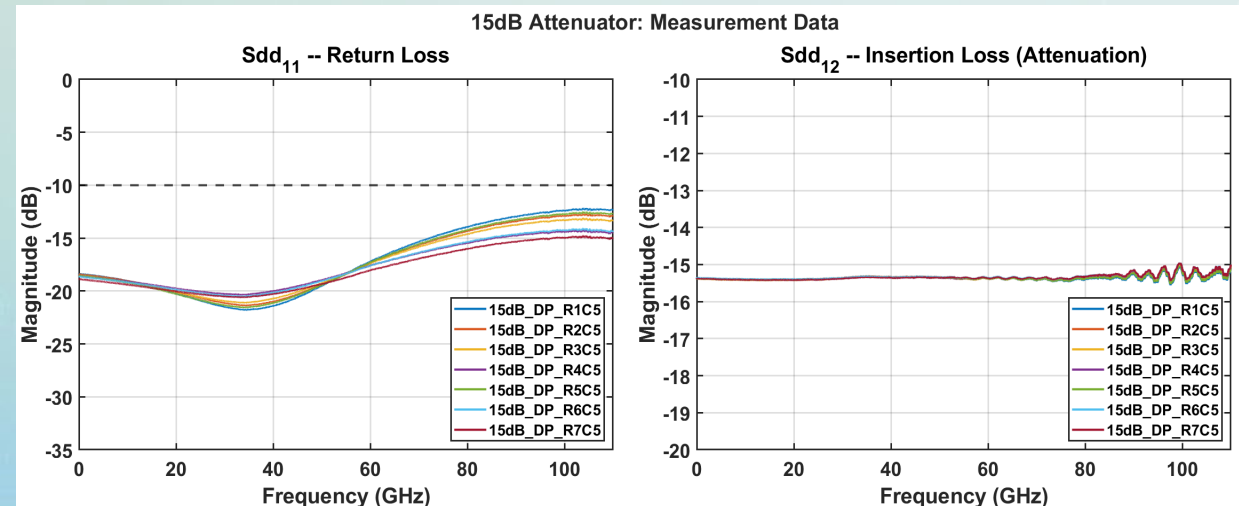
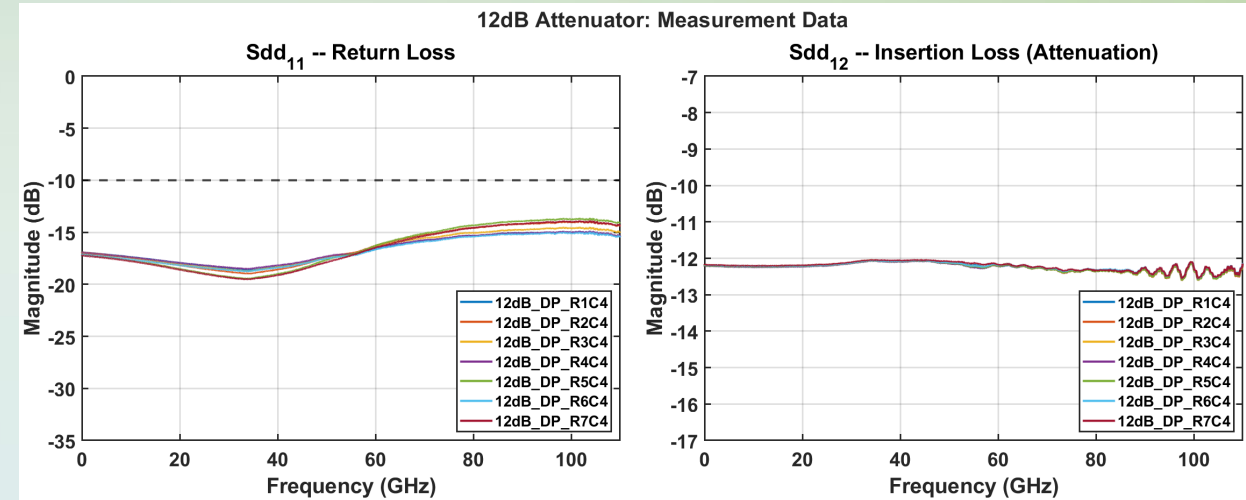
# 10dB Differential Pair

- Measured data matches very closely with 3D EM simulations.
- Over measured performance
  - RL < -12dB till 110GHz
  - IL - Variations less than  $\pm 0.5$ dB



# Other Value Differential Pair Attenuators

- Over measured performance
  - RL < -12dB till 110GHz
  - IL - Variations less than  $\pm 0.5$ dB



# Key Takeaways

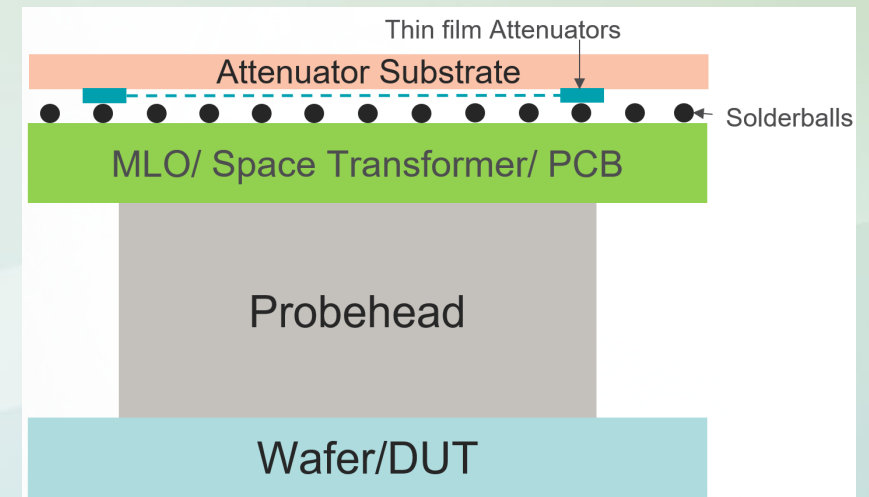
- Wide range of attenuation is possible
- Variation of <1dB for broadband frequencies (DC – 110GHz)
- Balanced and Unbalanced versions possible
- Wide range of resistor values
- Compact footprint for narrow pitch applications
- Better control on EM parasitics
- Solderball/reflowable on wafer
- Tolerant to resistance variations (Good fabrication tolerance)
- Balanced ground return upwards of 110GHz

# What's Next?



# Future Work

- System architecture showing thin film attenuators can be reflowed on the MLO/ space transformers or on PCBs or directly to the DUT.
- Other variations are possible
- Perform crosstalk measurements



**Patent:** P. Ghatе, D. Bock, “Broadband Attenuators using Thin Film for Wafer Sort,” Filed 2025 US Provisional Patent Application, Application Number: US63/760534.



# Questions

